





























## Exams for group S13-501

Fri, 22 Dec	09:00 — 12:00	ATT	Technology and Systems Integration Standards  Alekseenko I.V.  K-212
Sat, 23 Dec	09:00 — 12:00	ATT	Special Training  Androsov G.G.  K-212
Sat, 23 Dec	12:00 — 15:00	ATT	Principles of Digital Data Processing Application and Theory  Zaeva M.A.  K-911
Mon, 25 Dec	18:45 — 20:20	TEST	Complex System Risk Management  Evstifeev A.A.  K-911
Mon, 25 Dec	20:25 — 22:00	TEST	Production Organization and Planning  Evstifeev A.A.  K-911
Thu, 28 Dec	12:00 — 15:00	ATT	Technology of Chip Projects Design  Reshetko V.M.  K-911
Thu, 28 Dec	15:00 — 18:00	ATT	Professional Practice (Scientific Research ): Automatic Information Processing and Control Systems: Methods and Tools  Shuvalov V.B.  dep.12
Tue, 09 Jan	09:00 — 13:00	EXAM	Technology of Chip Projects Design  Reshetko V.M., Drevs Y.G.  K-911
Sat, 13 Jan	09:00 — 13:00	EXAM	Technology and Systems Integration Standards  Alekseenko I.V., Zalesskiy B.  K-213
Wed, 17 Jan	09:00 — 13:00	EXAM	Special Training  Kulik S.D.  K-212
Sat, 20 Jan	09:00 — 13:00	EXAM	Principles of Digital Data Processing Application and Theory  Zaeva M.A.  K-911
Mon, 22 Jan	09:00 — 13:00	EXAM	Professional Practice (Scientific Research ): Automatic Information Processing and Control Systems: Methods and Tools  Subgroup 1  Berezkin E.F., Drevs Y.G., Shuvalov V.B.  dep.12
Mon, 22 Jan	09:00 — 13:00	EXAM	Professional Practice (Scientific Research ): Automatic Information Processing and Control Systems: Methods and Tools  Subgroup 2  Shevchenko S.S., Ovcharenko E.S., Kulik S.D.  dep.12